

## Observation of interface modification of electrodeposited p-Cu<sub>2</sub>O thin films in an aqueous electrolyte

F.S.B. Kafi, K.M.D.C. Jayathileka, R.P. Wijesundera, W. Siripala<sup>1</sup>

Interface engineering via modification of semiconductor surfaces of junction devices is a powerful technique to improve the performance of devices. In addition, semiconductor material Cu<sub>2</sub>O has recently gained a considerable attention as a low cost semiconductor material suitable for developing thin film solar cells, water splitting in photoelectrochemical cells and gas sensors. Indeed, the possibility of relative band edge shifts of Cu<sub>2</sub>O with suitable interfacing materials will pave the way for interface engineering to improve the efficiency of those devices. In this study we have investigated this possibility of using electrodeposited p-type cuprous oxide thin films deposited using a lactate bath containing 3 M sodium lactate and 0.4 M CuSO<sub>4</sub> at various pH values. These Cu<sub>2</sub>O films were used in a photoelectrochemical cell to form semiconductor/electrolyte junctions in a 0.1 M sodium acetate aqueous solution and then to measure the flat band potential variations with the pH of the Cu<sub>2</sub>O film deposition baths. It was observed that pH value of the Cu<sub>2</sub>O film deposition bath is very sensitive to the flat band potential. This result gives a direct evidence that the surface of Cu<sub>2</sub>O film is modified at the Cu<sub>2</sub>O/electrolyte interface producing a relative band edge shift yielding the observed flat band shifts. We observed a general trend of flat band potential shift of about 350 mV in the positive direction, as the pH of the deposition bath was changed from 7 to 12.5. The observed shift in the flat band potential in the positive direction is very useful for the water splitting reaction because the valence band edge of Cu<sub>2</sub>O is shifted positively relative to the oxygen redox potential. Our observation of highest photoresponse for Cu<sub>2</sub>O thin films prepared at pH 13.5 is a direct evidence for the positive shift of the band edges. The observation of the interface modification of Cu<sub>2</sub>O in aqueous electrolyte may be further extended to other suitable interfaces for developing Cu<sub>2</sub>O based junction devices.

*Key words: Cuprous oxide, Electrodeposition, Interface engineering, flat band potential*

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<sup>1</sup> Department of Physics, University of Kelaniya, Sri Lanka. palitha@kln.ac.lk